

U.S. Department of Commerce, Patent and Trademark				Atty. Docket No.		Application No.		
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				BTAT.002US1		09/832,933		
				Applicant(s)		Conf. No.		
(Use several sheets if necessary)				Wu et al.		5253		
(Form PTO-1449)				Filing Date		Art Group		
				April 11, 2001		2123		
<b>U.S. Patent Documents</b>								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
TS	1	7,003,755	2/2006	Pang et al.				
TS	2	6,209,122	03/2001	Jyu et al.				
TS	3	6,058,496	05/2000	Gillis et al.				
TS	4	6,524,872	02/2003	Cheung				
TS	5	5,600,844	02/1997	Shaw et al.				
<b>U.S. Published Patent Application Documents</b>								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<b>Foreign Patent Documents</b>								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>								
TS	6	Kuo, et al., "Simulation of MOSFET Lifetime under AC Hot-Electron Stress," <i>IEEE Transactions on Electron Devices</i> , Vol. 35, No. 7, July, 1988, pp. 1004-1011.						
TS	7	Chen, "A Unified Compact Scalable Id Model for Hote Carrier Reliability Simulation," <i>IEEE</i> , March 1999, pp. 243-248.						
TS	8	Leblebici et al., "An Integrated Hot-Carrier Degradation Simulator for VLSI Reliability Analysis," <i>Proceeding ICCAD, IEEE</i> , 1990, pp. 400-403.						
TS	9	Quader et al., "Hot-Carrier-Reliability Design Rules for Translating Device Degradation to CMOS Digital Circuit Degradation," <i>IEEE Transactions on Electron Devices</i> , Vol. 41, No. 4, May 1994, pp. 681-691.						
Examiner			Date Considered /Thomas Stevens/ (12/04/2006)					
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.								